

<b>Notice of References Cited</b>	Application/Control No. 10/791,914		Applicant(s)/Patent Under Reexamination CHEE ET AL.	
	Examiner Kenan Cehic		Art Unit 2609	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,383,177 A	01-1995	Tateishi, Hiroomi	370/250
*	B	US-2003/0061581 A1	03-2003	Baumgartner et al.	716/4
*	C	US-2003/0142629 A1	07-2003	Krishnamurthi et al.	370/249
*	D	US-2003/0179777 A1	09-2003	Denton et al.	370/503
*	E	US-2004/0223458 A1	11-2004	Gentle, Christopher Reon	370/230
*	F	US-2005/0216954 A1	09-2005	Ramaiah et al.	726/022
*	G	US-2006/0209709 A1	09-2006	Kovacevic, Branko D.	370/252
*	H	US-2007/0008897 A1	01-2007	Denton et al.	370/250
*	I	US-2007/0147257 A1	06-2007	Oskouy et al.	370/238
*	J	US-2007/0168748 A1	07-2007	Musoll, Enrique	714/038
*	K	US-2002/0089931	07-2002	Takada et al.	370/232
*	L	US-5,633,742	05-1997	Shipley, Robert T.	398/118
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.